

Ion beam microscopy in serve of material investigations

Tuesday, 3 December 2019 14:55 (15)

High-energy ion microscopes attached to an ion accelerator system are highly versatile research instruments for applications in high-resolution material investigations capable of precise tuning for a given sample or task. Their design and flexibility is usually closely related to properties of the accelerator system. We used a suite of ion nanobeams (proton, alpha, carbon and oxygen ions) with magnetic rigidity (ME/q^2) value up to 40 MeV amu/e² provided by the high-energy ion microscope of accelerator facility at ANSTO for here presented material investigation studies of micron-sized sample structures or micron-sized particles from very different origins. Examples include bio systems, health, electronics, manufacturing and cultural heritage.

Keywords: material, structure, microscopy, ion nanobeam

*Corresponding author: zkp@ansto.gov.au

Speakers Gender

Male

Travel Funding

No

Level of Expertise

Expert

Do you wish to take part in the poster slam

Primary author(s) : PASTUOVIC, Zeljko (Centre for Accelerator Science of ANSTO)

Presenter(s) : PASTUOVIC, Zeljko (Centre for Accelerator Science of ANSTO)

Session Classification : Session 20

Track Classification : Imaging